



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AOC3862**

**12V Common-Drain Dual N-Channel MOSFET**

### General Description

- Trench Power MOSFET technology
- Low  $R_{SS(ON)}$
- With ESD protection to improve battery performance and safety
- Common drain configuration for design simplicity
- RoHS and Halogen-Free Compliant

### Applications

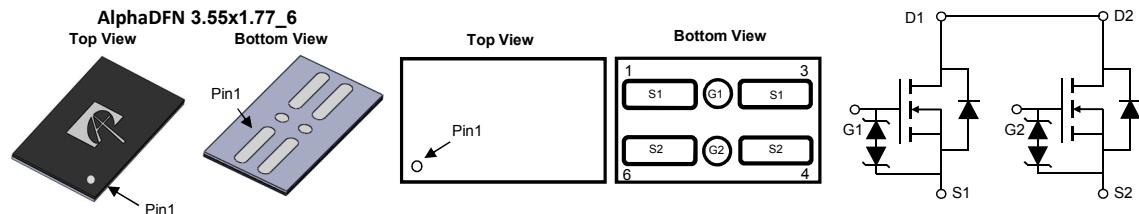
- Battery protection switch
- Mobile device battery charging and discharging

### Product Summary

$V_{SS}$	12V
$R_{SS(ON)}$ (at $V_{GS}=4.5V$ )	< 3mΩ
$R_{SS(ON)}$ (at $V_{GS}=4.0V$ )	< 3.1mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.8V$ )	< 3.2mΩ
$R_{SS(ON)}$ (at $V_{GS}=3.1V$ )	< 3.5mΩ
$R_{SS(ON)}$ (at $V_{GS}=2.5V$ )	< 4.4mΩ

### Typical ESD protection

HBM Class 2



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOC3862	AlphaDFN 3.55x1.77_6	Tape & Reel	5000

### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Rating	Units
Source-Source Voltage	$V_{SS}$	12	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Source Current(DC) <sup>Note1</sup>	$I_S$   $T_A=25^\circ\text{C}$	27	A
Source Current(Pulse) <sup>Note2</sup>	$I_{SM}$	100	
Power Dissipation <sup>Note1</sup>	$P_D$   $T_A=25^\circ\text{C}$	2.5	W
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typical	Units
Maximum Junction-to-Ambient   $t \leq 10\text{s}$	$R_{\theta JA}$	40	°C/W
Maximum Junction-to-Ambient   Steady-State		50	°C/W

**Note 1.**  $I_S$  rated value is based on bare silicon. Mounted on 70mmx70mm FR-4 board.

**Note 2.** PW <10  $\mu\text{s}$  pulses, duty cycle 1% max.

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
<b>STATIC PARAMETERS</b>							
$\text{BV}_{\text{SSS}}$	Source-Source Breakdown Voltage	$I_S=250\mu\text{A}, V_{GS}=0\text{V}$	Test Circuit 6	12		V	
$I_{\text{SSS}}$	Zero Gate Voltage Source Current	$V_{SS}=12\text{V}, V_{GS}=0\text{V}$	Test Circuit 1		1	$\mu\text{A}$	
			$T_J=55^\circ\text{C}$		5		
$I_{GSS}$	Gate leakage current	$V_{SS}=0\text{V}, V_{GS}=\pm 8\text{V}$	Test Circuit 2		$\pm 10$	$\mu\text{A}$	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{SS}=V_{GS}, I_S=250\mu\text{A}$	Test Circuit 3	0.4	0.8	1.2	V
$R_{SS(\text{ON})}$	Static Source to Source On-Resistance	$V_{GS}=4.5\text{V}, I_S=5\text{A}$	Test Circuit 4	1.7	2.38	3.0	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$		2.3	3.3	4.1	
		$V_{GS}=4.0\text{V}, I_S=5\text{A}$	Test Circuit 4	1.75	2.45	3.1	$\text{m}\Omega$
		$V_{GS}=3.8\text{V}, I_S=5\text{A}$	Test Circuit 4	1.8	2.5	3.2	$\text{m}\Omega$
		$V_{GS}=3.1\text{V}, I_S=5\text{A}$	Test Circuit 4	1.9	2.7	3.5	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{SS}=5\text{V}, I_S=5\text{A}$	Test Circuit 4	2.2	3.2	4.4	$\text{m}\Omega$
			Test Circuit 3		50		
$V_{FSS}$	Forward Source to Source Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$	Test Circuit 5		0.65	1	V
<b>DYNAMIC PARAMETERS</b>							
$R_g$	Gate resistance	$f=1\text{MHz}$			1.2	$\text{k}\Omega$	
<b>SWITCHING PARAMETERS</b>							
$Q_g$	Total Gate Charge	$V_{G1S1}=4.5\text{V}, V_{SS}=6\text{V}, I_S=5\text{A}$		46		nC	
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{G1S1}=4.5\text{V}, V_{SS}=6\text{V}, R_L=1.2\Omega,$ $R_{\text{GEN}}=3\Omega$		2.5		$\mu\text{s}$	
$t_r$	Turn-On Rise Time			5.5		$\mu\text{s}$	
$t_{D(\text{off})}$	Turn-Off DelayTime		Test Circuit 8	4		$\mu\text{s}$	
$t_f$	Turn-Off Fall Time			11		$\mu\text{s}$	

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

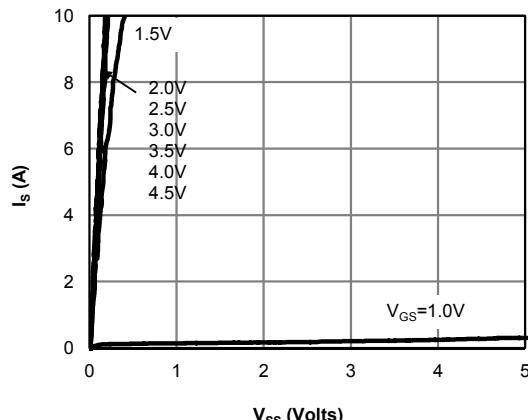


Figure 1: On-Region Characteristics

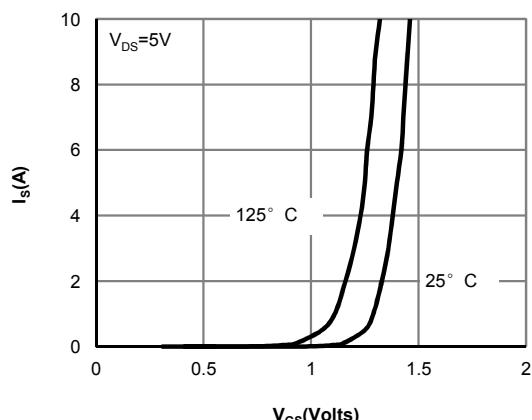


Figure 2: Transfer Characteristics

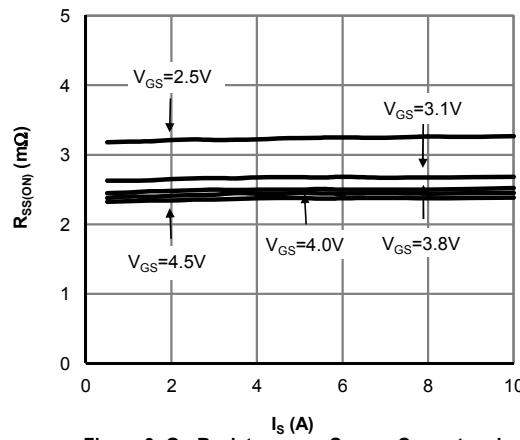


Figure 3: On-Resistance vs. Source Current and Gate Voltage

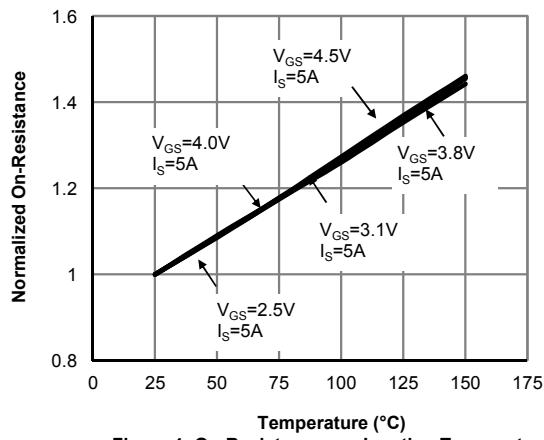


Figure 4: On-Resistance vs. Junction Temperature

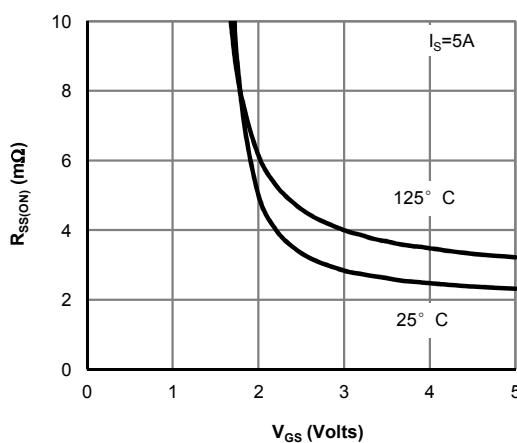


Figure 5: On-Resistance vs. Gate-Source Voltage

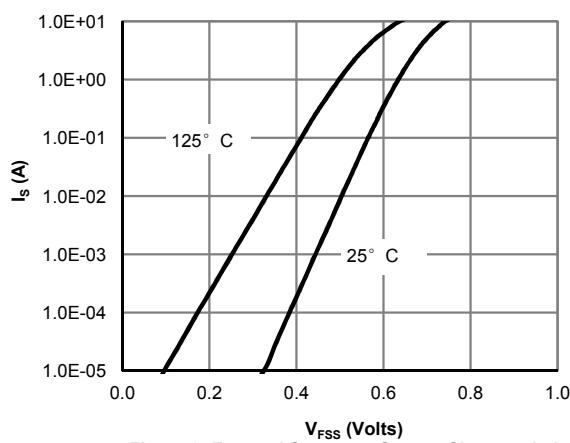


Figure 6: Forward Source to Source Characteristics



### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

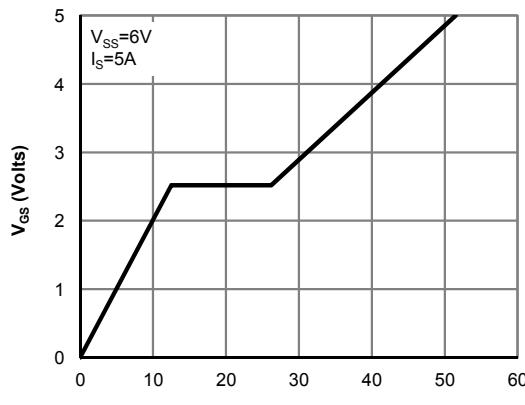


Figure 7: Gate-Charge Characteristics

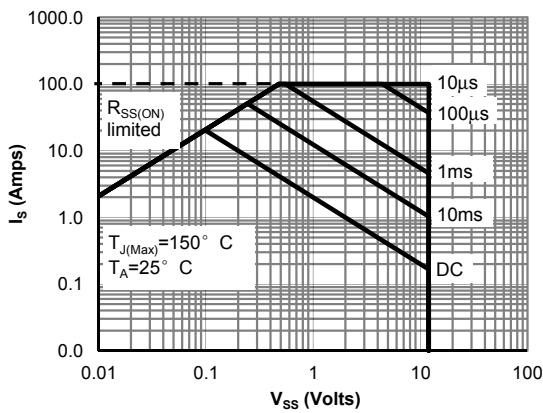


Figure 8: Maximum Forward Biased Safe Operating Area (Note1)

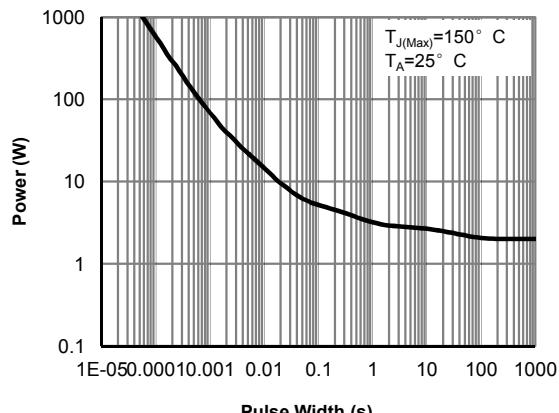


Figure 9: Single Pulse Power Rating Junction-to-Ambient (Note1)

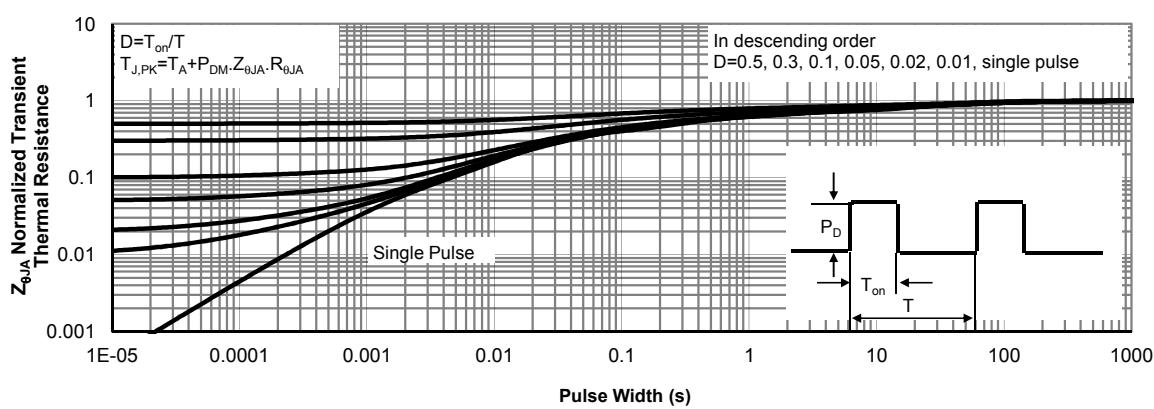
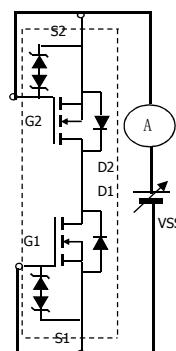
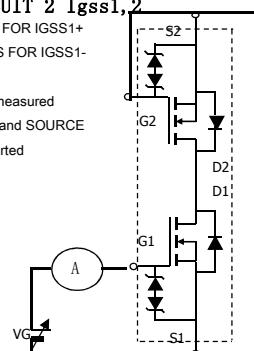


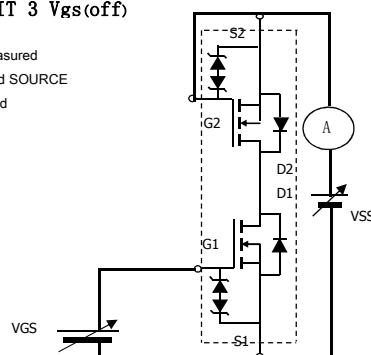
Figure 10: Normalized Maximum Transient Thermal Impedance (Note1)

**TEST CIRCUIT 1 Isss**  
 POSITIVE VSS FOR ISSS+  
 NEGATIVE VSS FOR ISSS-

**TEST CIRCUIT 2 Igss1,2**  
 POSITIVE VGS FOR IGSS1+  
 NEGATIVE VGS FOR IGSS1-

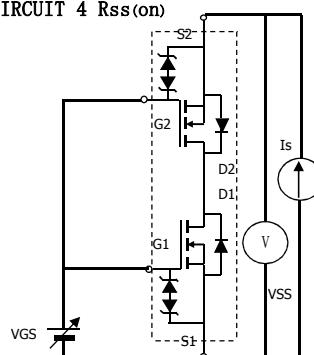
When FET1 is measured  
between GATE and SOURCE  
of FET2 are shorted


**TEST CIRCUIT 3 Vgs(off)**

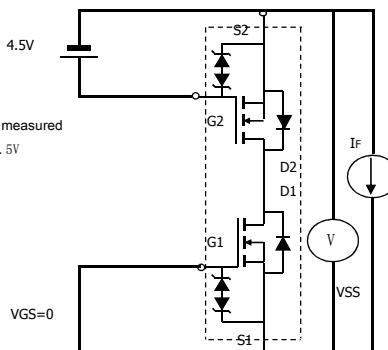
When FET1 is measured  
between GATE and SOURCE  
of FET2 are shorted

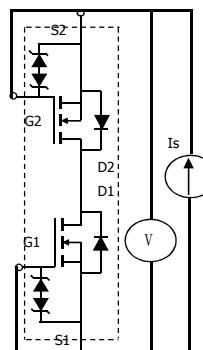

**TEST CIRCUIT 4 Rss(on)**

Vss/Is

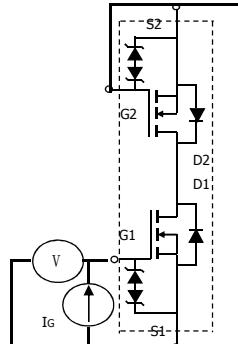

**TEST CIRCUIT 5 VF(ss)1,2**

When FET1 measured  
FET2 VGS=4.5V


**TEST CIRCUIT 6 BVdss**

 POSITIVE VSS FOR ISSS+  
 NEGATIVE VSS FOR ISSS-

**TEST CIRCUIT 7 BVgs01,2**  
 POSITIVE VSS FOR ISSS+  
 NEGATIVE VSS FOR ISSS-

When FET1 is measured  
between GATE and SOURCE  
of FET2 are shorted


**TEST CIRCUIT 8**  
 Switching time
